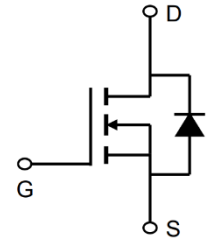


30V N-Channel Enhancement Mode MOSFET

Description

The AP80N03NF uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



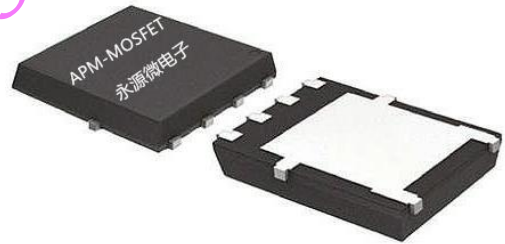
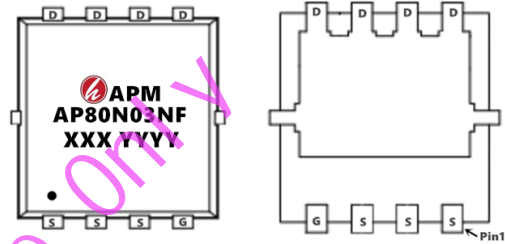
General Features

$V_{DS} = 30V$ $I_D = 80A$

$R_{DS(ON)} < 4.0m\Omega$ @ $V_{GS}=10V$

Application

- Battery protection
- Load switch
- Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80N03NF	PDFN5*6-8L	AP80N03NF XXX YYYYY	5000

Absolute Maximum Ratings (TC=25 °C unless otherwise noted)

Symbol	Parameter	Max	Units
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	80	A
$I_D@T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^{1,6}$	65	A
I_{DM}	Pulsed Drain Current ^{note1}	400	A
EAS	Single Pulsed Avalanche Energy ^{note2}	320	mJ
IAS	Avalanche Current	45.8	A
TSTG	Storage Temperature Range	-55 to 175	°C
T_J	Operating Junction Temperature Range	-55 to 175	°C
$P_D@T_C=25^\circ C$	Total Power Dissipation ⁴	88	W
$P_D@T_A=25^\circ C$	Total Power Dissipation ⁴	44	W
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	58	°C/W
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹ (t ≤ 10s)	20	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	2.3	°C/W

30V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V,	-	-	1.0	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	1.5	2.5	V
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} =10V, I _D =24A	-	2.9	4.0	mΩ
R _{DS(on)}	Static Drain-Source on-Resistance	V _{GS} =4.5V, I _D =12A	-	5.3	6.5	
R _G	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1.0MHz	-	-	3.3	Ω
g _{FS}	Forward Transconductance	V _{DS} =10V, I _D =10A	-	15.5	-	S
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	2200	-	pF
C _{oss}	Output Capacitance		-	280	-	pF
C _{rss}	Reverse Transfer Capacitance		-	177	-	pF
Q _g	Total Gate Charge	V _{DS} =15V, I _D =24A, V _{GS} =10V	-	42	-	nC
Q _{gs}	Gate-Source Charge		-	4	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	13	-	nC
t _{d(on)}	Turn-on Delay Time	V _{DD} =15V, I _D =15A, R _{GEN} =3.3Ω, V _{GS} =10V	-	12.6	-	ns
t _r	Turn-on Rise Time		-	19.5	-	ns
t _{d(off)}	Turn-off Delay Time		-	42.8	-	ns
t _f	Turn-off Fall Time		-	13.2	-	ns
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	-	-	100	A
I _{SM}	Pulsed Source Current ^{2,5}		-	-	400	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =30A	-	-	1.2	V
t _{rr}	Body Diode Reverse Recovery Time	I _F =30A, dI/dt=100A/μs	-	19	-	ns
Q _{rr}	Body Diode Reverse Recovery Charge		-	11	-	nC

Note :

- The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- The data tested by pulsed, pulse width ≅ 300us, duty cycle ≅ 2%
- The EAS data shows Max. rating. The test condition is V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=45.8A
- The power dissipation is limited by 175°C junction temperature
- The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.
- Package limitation current is 85A.

Typical Characteristics

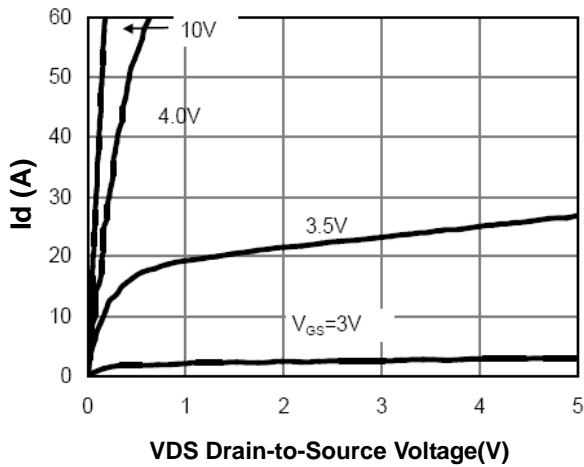


Figure 1. Output Characteristics

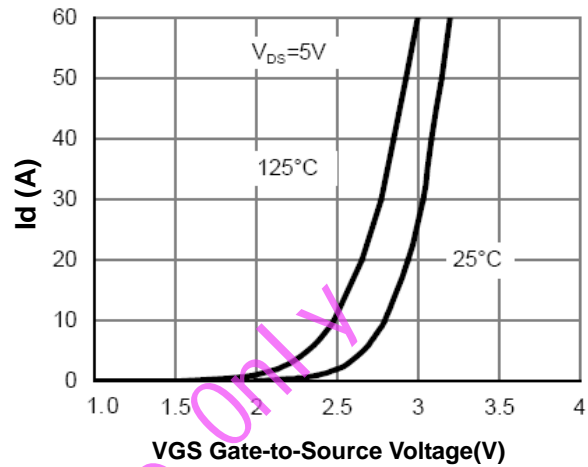


Figure 2. Transfer Characteristics

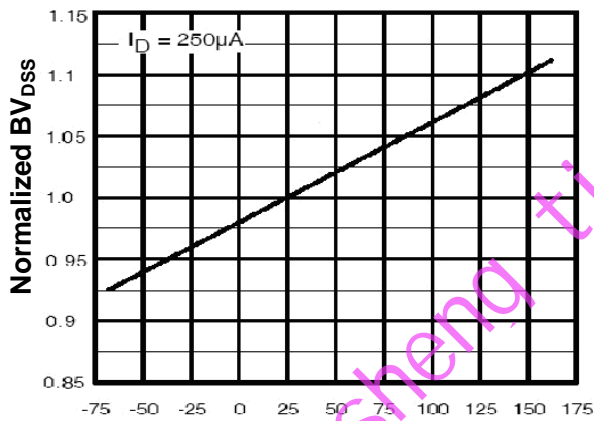


Figure 3. Max BV_{DSS} vs Junction Temperature

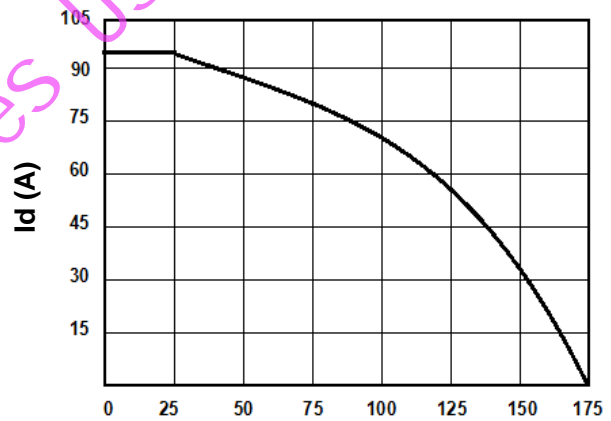


Figure 4. Drain Current

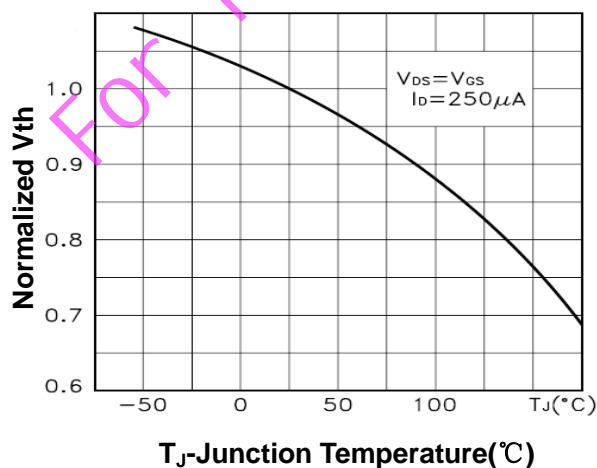


Figure 5. $V_{GS(th)}$ vs Junction Temperature

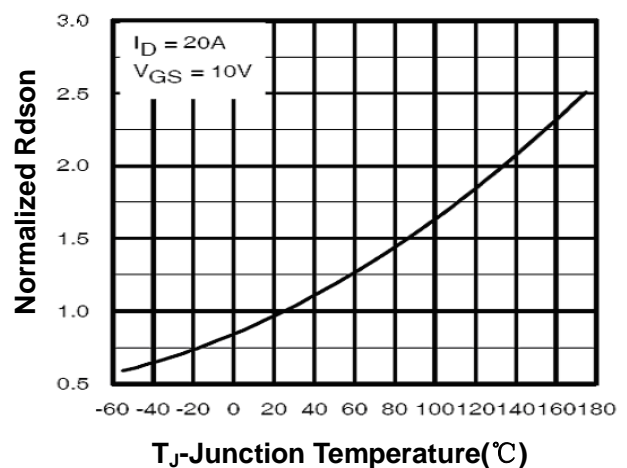


Figure 6. $R_{DS(on)}$ vs Junction Temperature

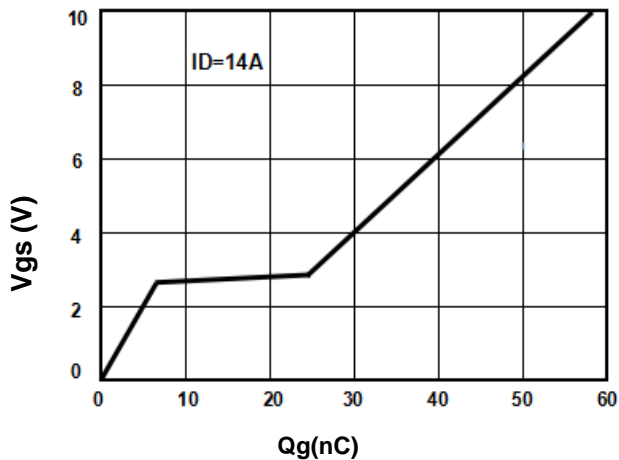


Figure 7. Gate Charge Waveforms

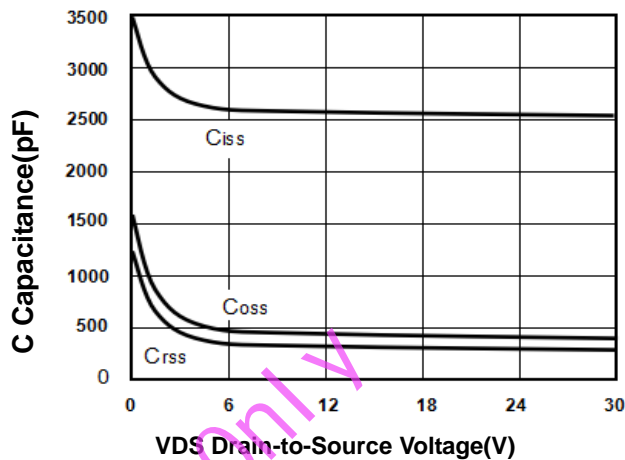


Figure 8. Capacitance

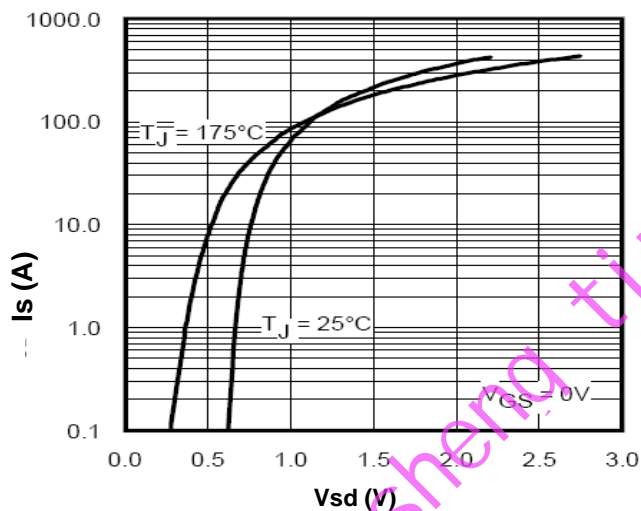


Figure 9. Body-Diode Characteristics

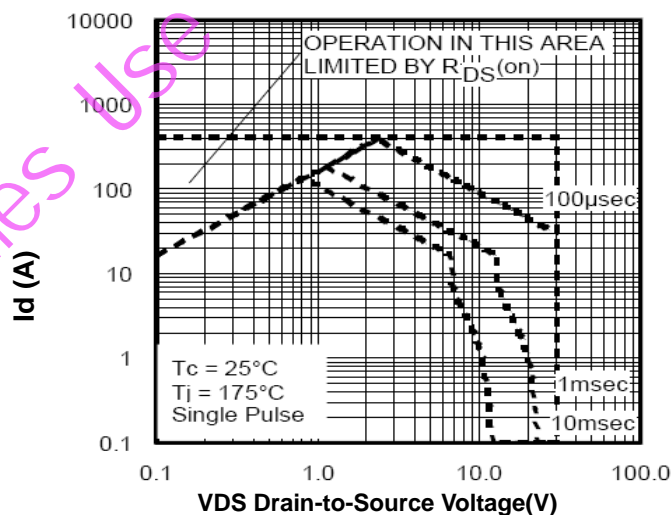


Figure 10. Maximum Safe Operating Area

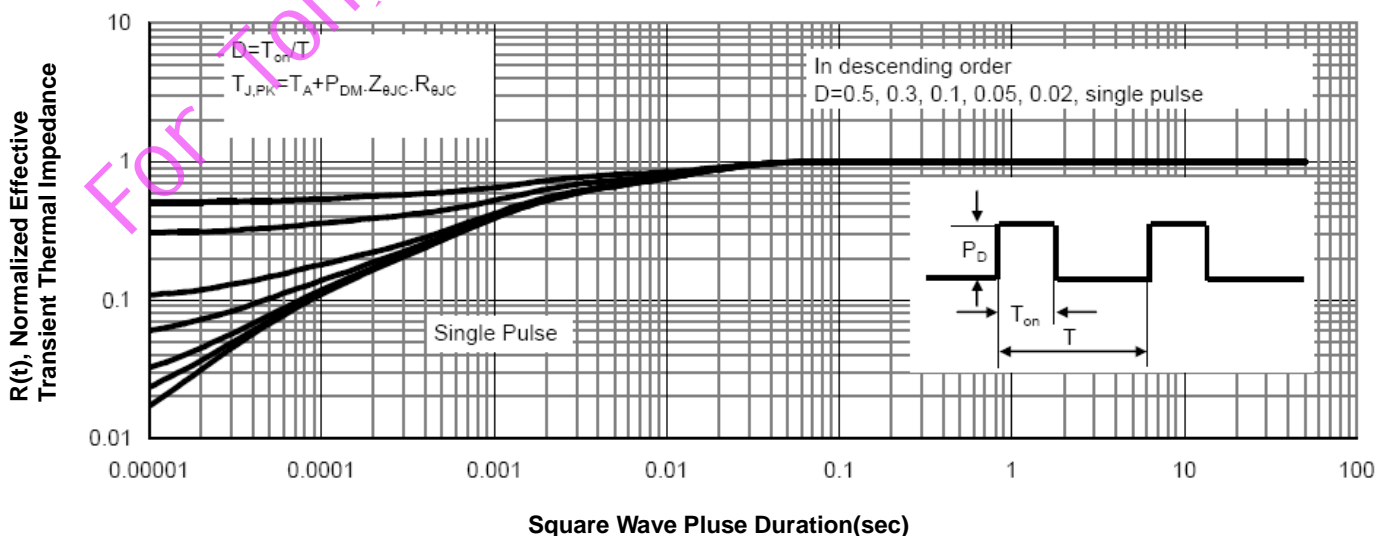
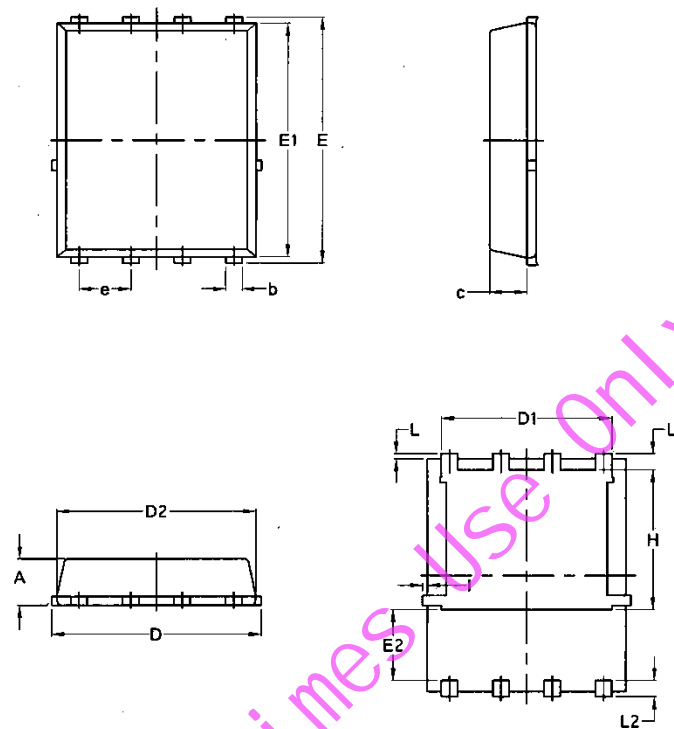


Figure 11. Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-DFN5*6-8L-JQ Single



Symbol	Common			
	mm		Inch	
	Mim	Max	Min	Max
A	1.03	1.17	0.0406	0.0461
b	0.34	0.48	0.0134	0.0189
c	0.824	0.0970	0.0324	0.082
D	4.80	5.40	0.1890	0.2126
D1	4.11	4.31	0.1618	0.1697
D2	4.80	5.00	0.1890	0.1969
E	5.95	6.15	0.2343	0.2421
E1	5.65	5.85	0.2224	0.2303
E2	1.60	/	0.0630	/
e	1.27 BSC		0.05 BSC	
L	0.05	0.25	0.0020	0.0098
L1	0.38	0.50	0.0150	0.0197
L2	0.38	0.50	0.0150	0.0197
H	3.30	3.50	0.1299	0.1378
I	/	0.18	/	0.0070

30V N-Channel Enhancement Mode MOSFET

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AP80N03NF

30V N-Channel Enhancement Mode MOSFET

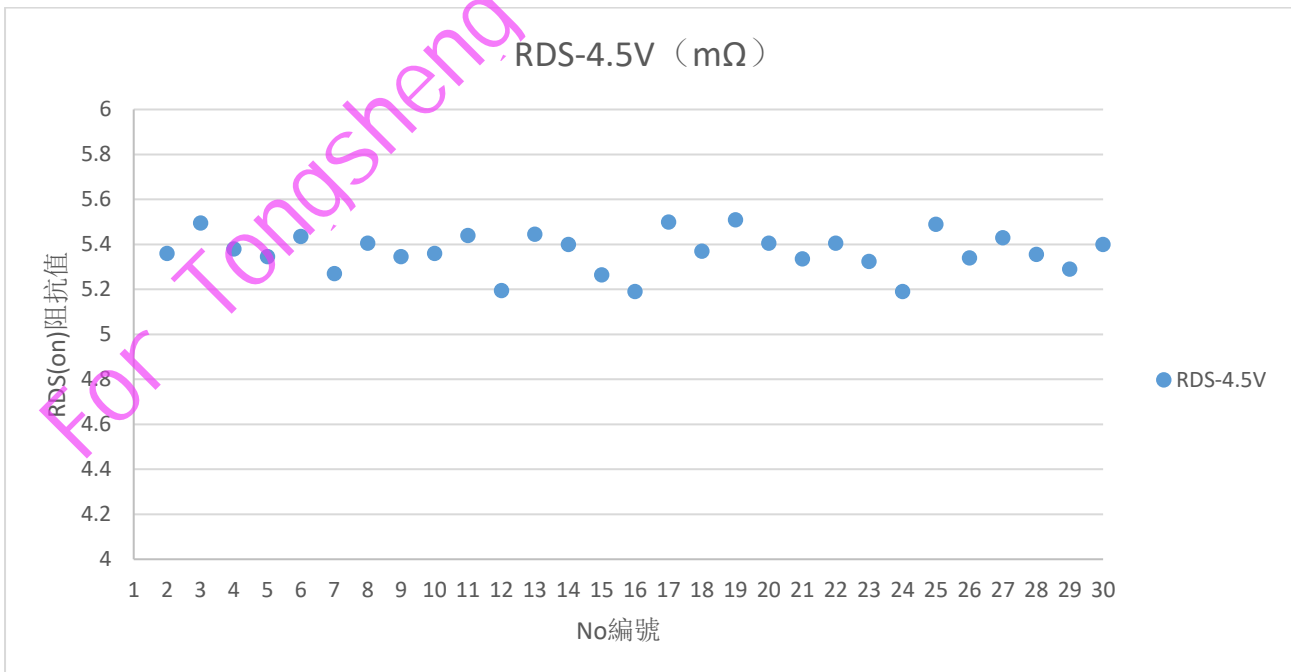
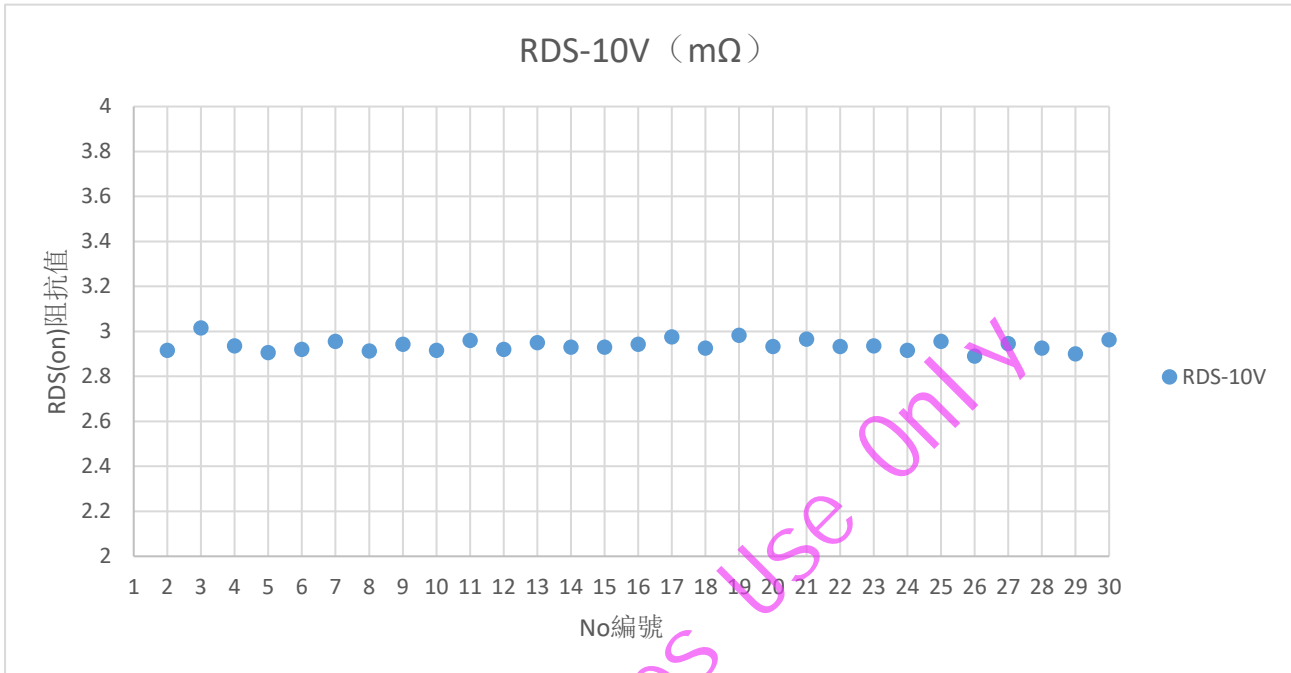
Edition	Date	Change
Rve1.0	2019/8/1	Initial release

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Test Report For 30PCS (30pcs 典型測試報告)



30V N-Channel Enhancement Mode MOSFET

